

Notice of References Cited

Application/Control No.

09/771,091 ✓

Applicant(s)/Patent Under
Reexamination
BAUER, DANIEL

Examiner

Van Kim T. Nguyen

Art Unit

2661

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,717,920	04-2004	Cheng, Dean	370/255
*	B	US-6,697,333	02-2004	Bawa et al.	370/238
*	C	US-6,690,671	02-2004	Anbiah et al.	370/395.43
*	D	US-6,687,229	02-2004	Kataria et al.	370/238
*	E	US-6,633,544	10-2003	Rexford et al.	370/238
*	F	US-6,628,670	09-2003	Galand et al.	370/468
*	G	US-6,621,798	09-2003	Krishnan et al.	370/256
*	H	US-6,600,724	07-2003	Cheng, Dean	370/256
*	I	US-6,560,654	05-2003	Fedyk et al.	709/239
*	J	US-6,370,119	04-2002	Basso et al.	370/252
*	K	US-6,256,309	07-2001	Daley et al.	370/395.43
*	L	US-2002/0015386	02-2002	Kajiwara, Yasuhiro	370/351
*	M	US-2001/0015958	08-2001	Iliadis, Ilias	370/238

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.